Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/814,144	NAKAMURA, MITSUAKI	
Examiner	Art Unit	
Xavier Szewai Wong	2616	



SEARCHED					
Class	Subclass	Date	Examiner		
370 ·	<b>512</b>	8/4/2007	xsw		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	8/4/2007	xsw
Inventor Name and Assignee search in PALM ExPO and EAST	8/4/2007	XSW
esp@cenet	8/4/2007	XSW
370/512,216-220.ccls.	8/5/2007	XSW
priorit\$3 and synchroni\$6	8/5/2007	xsw
(transmi\$6) same (multiply\$3 multiplication) same priority	8/5/2007	XSW
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